Se	Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/601,034	GOODMAN ET AL.	
Examiner	Art Unit	
Djenane M. Bayard	2141	

Djenane M. Bayard

	SEARCHED		
01	0.1-1	Dete	Examiner
Class	Subclass	Date	Examiner
709	206	12/18/2007	DB
713	212	12/18/2007	db

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		•	

(INOCODINO OEAN	(INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
east ·	12/18/2007	db		
<u> </u>	,			
Consulted with L. Luu	12/14/2007	DB		
Consulted with L. Luu	12/14/2007	DB		
•				